

ABSTRACT OF THE DISCLOSURE

An electromagnetic field analyzer (11) finally replaces a fill metal pattern in a wiring pattern library (32) with an insulator of high dielectric constant, and stores, in a
5 capacitance value data base (33), parasitic capacitance value information in which values of parasitic capacitances parasiting the insulator and fill metal patterns are in correspondence. A regression analyzer (12) stores, in a regression equation data base (36), regression equation information for deriving parasitic capacitance values from the fill metal patterns and associated size information. A parasitic capacitance extractor
10 (13) obtains values of parasitic capacitances parasiting the replacing insulator for outputting parasitic capacitance information (37) while applying a regression equation of the regression equation information to the size information associated with the fill metal patterns.